

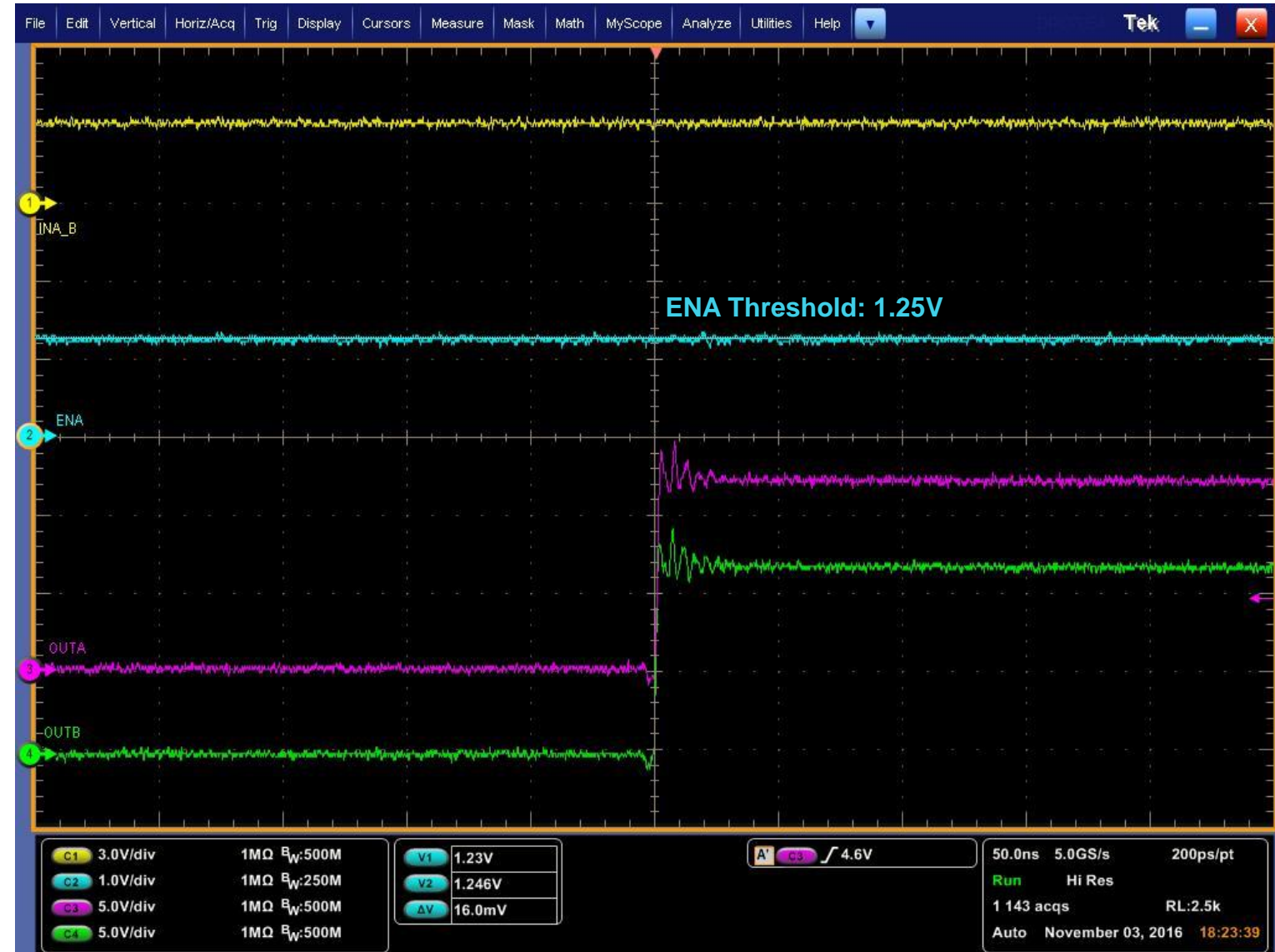
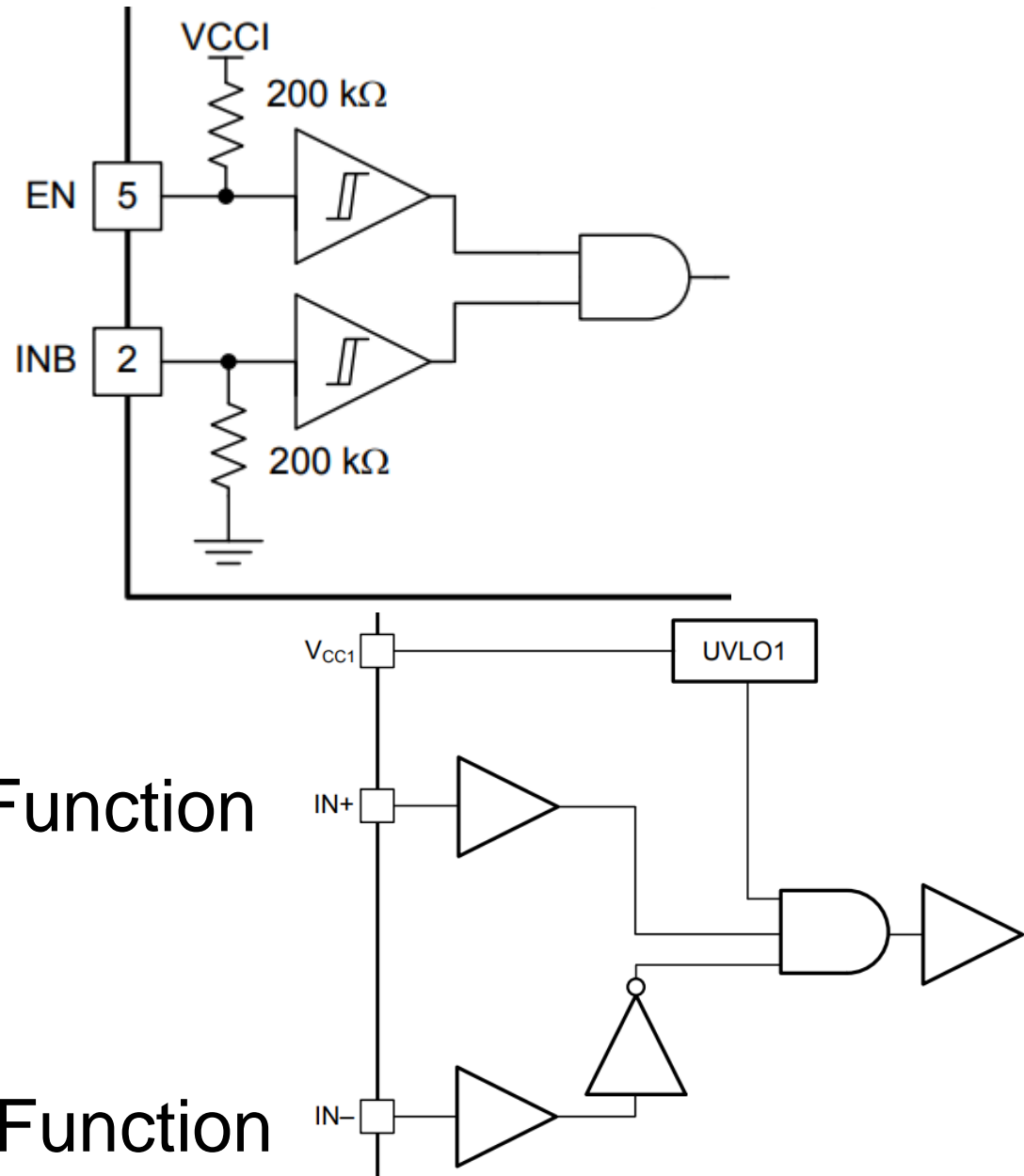
Isolated gate driver challenges and solutions

TIPL 504

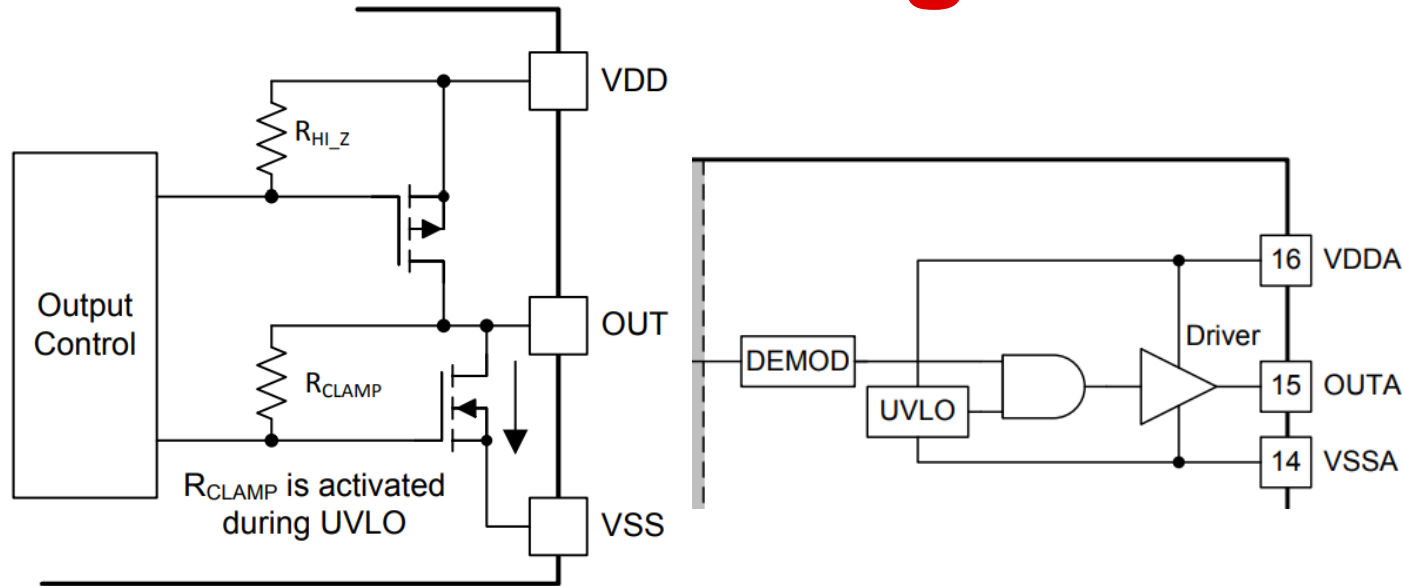
TI Precision Labs – Isolated Gate Drivers

Presented and Prepared by Derek Payne

General Challenges – Enable/Disable



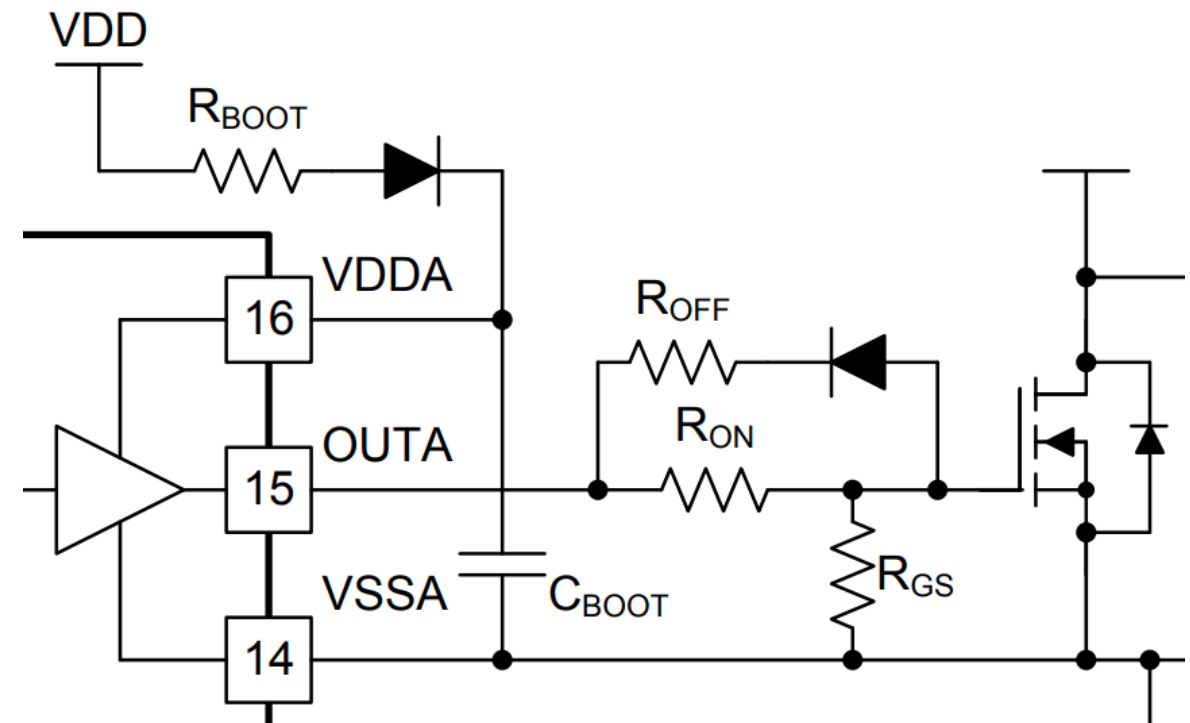
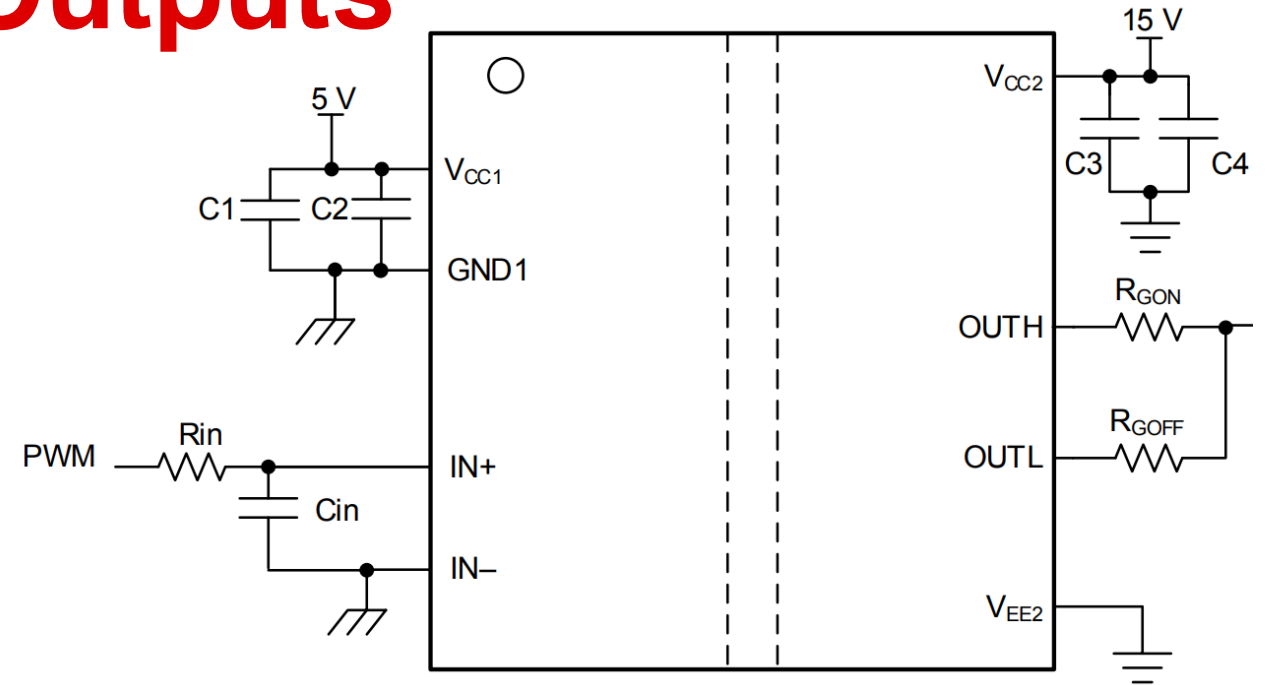
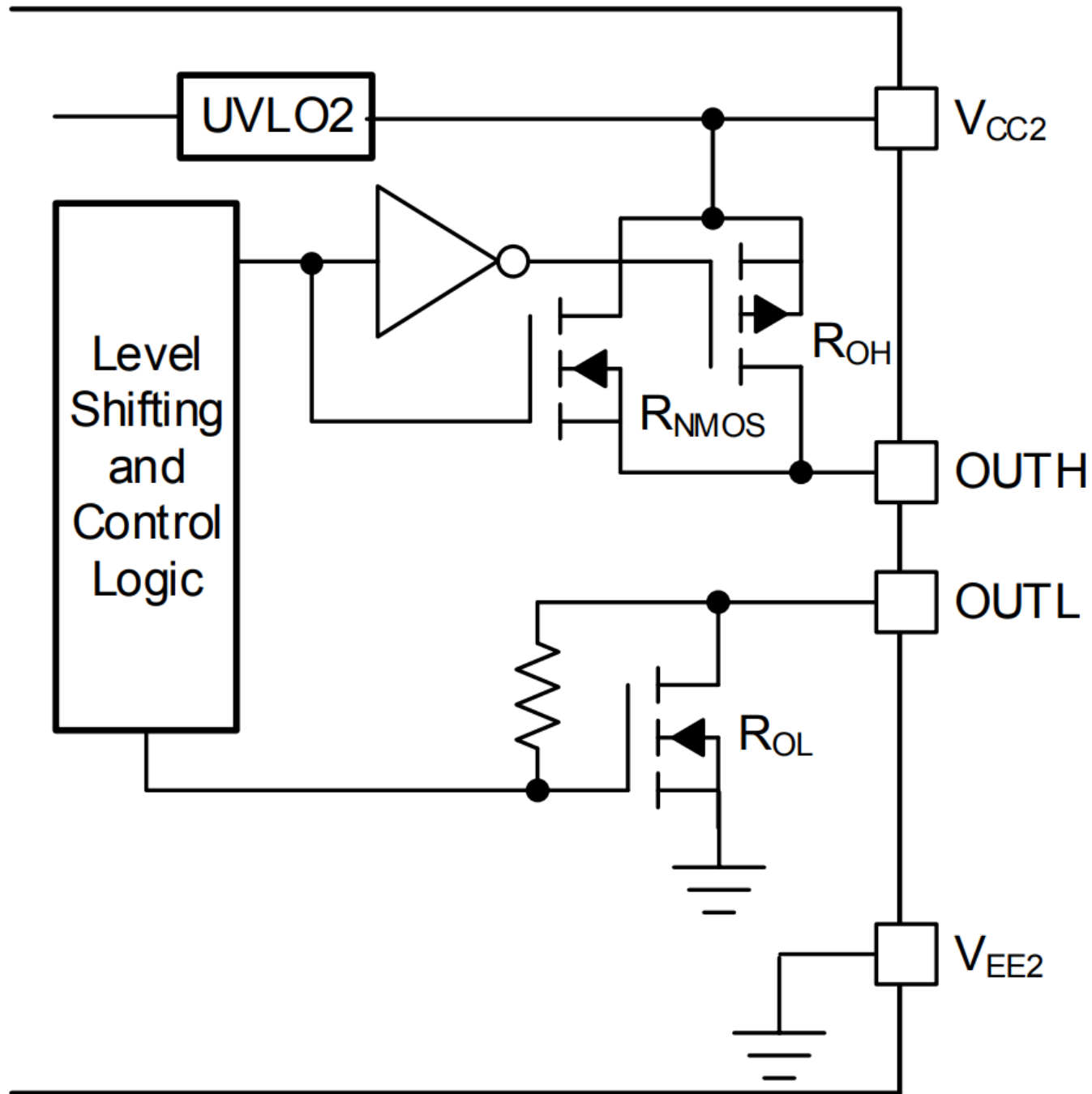
General Challenges – Undervoltage Lockout



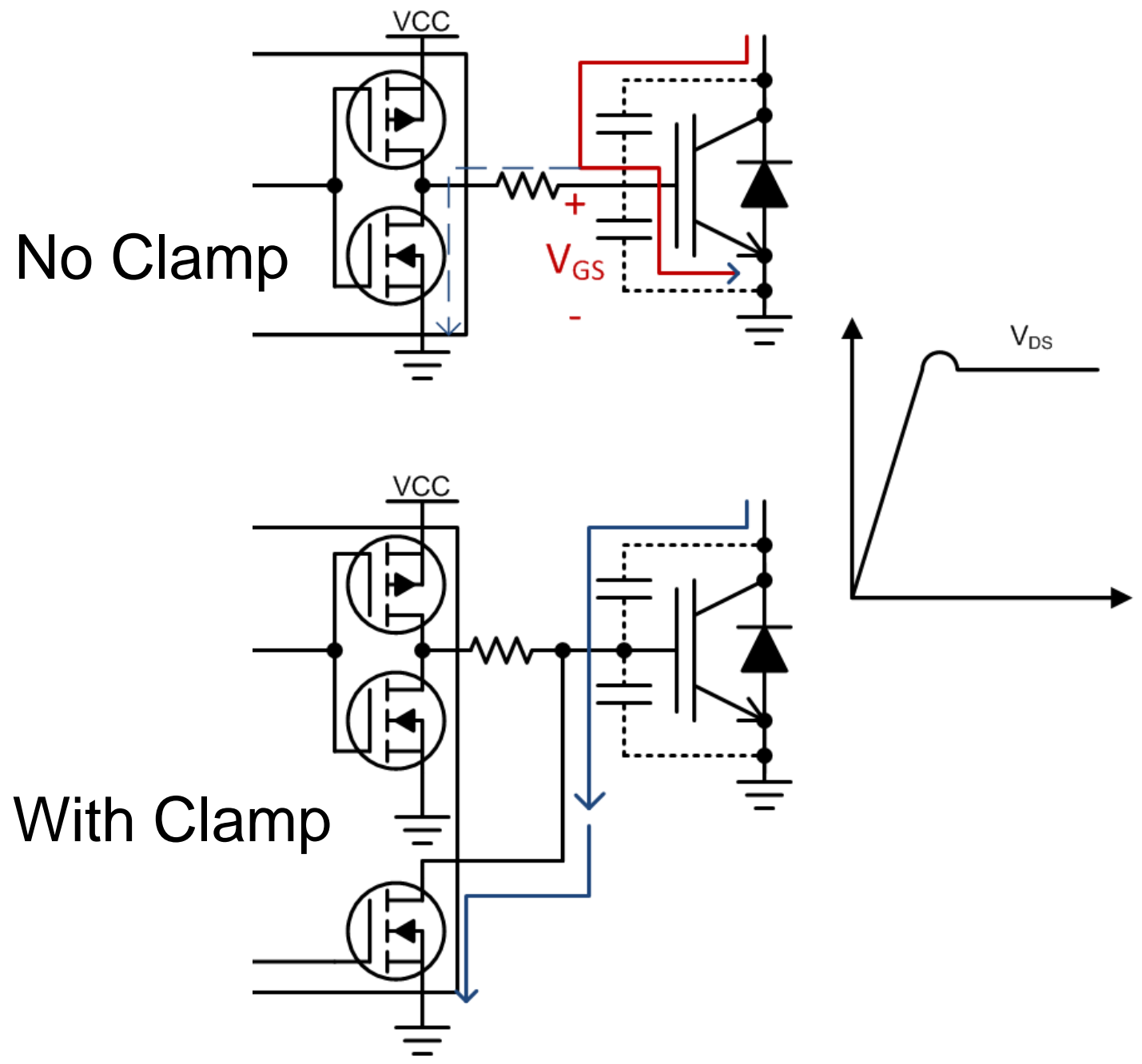
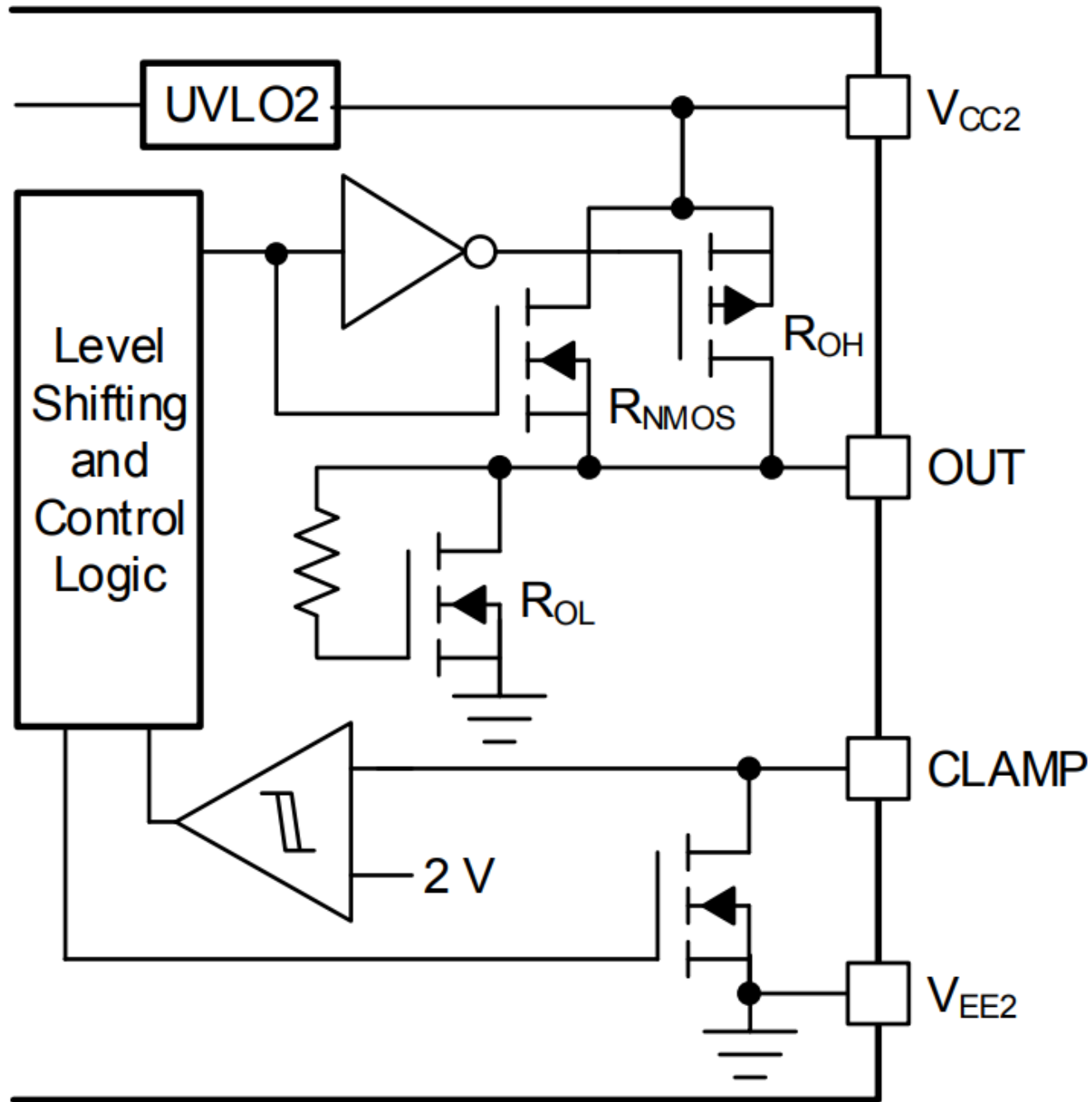
VCCI UVLO THRESHOLDS						
V _{VCCI_ON}	Rising threshold		2.55	2.7	2.85	V
V _{VCCI_OFF}	Falling threshold VCCI_OFF		2.35	2.5	2.65	V
V _{VCCI_HYS}	Threshold hysteresis			0.2		V
UCC21521ADW UVLO THRESHOLDS (5-V UVLO VERSION)						
V _{VDDA_ON} , V _{VDDB_ON}	Rising threshold VDDA_ON, VDDB_ON		5.2	5.8	6.3	V
V _{VDDA_OFF} , V _{VDDB_OFF}	Falling threshold VDDA_OFF, VDDB_OFF		4.9	5.5	6	V
V _{VDDA_HYS} , V _{VDDB_HYS}	Threshold hysteresis			0.3		V
UCC21521DW UVLO THRESHOLDS (8-V UVLO VERSION)						
V _{VDDA_ON} , V _{VDDB_ON}	Rising threshold VDDA_ON, VDDB_ON		8	8.5	9	V
V _{VDDA_OFF} , V _{VDDB_OFF}	Falling threshold VDDA_OFF, VDDB_OFF		7.5	8	8.5	V
V _{VDDA_HYS} , V _{VDDB_HYS}	Threshold hysteresis			0.5		V
UCC21521CDW UVLO THRESHOLDS (12-V UVLO VERSION)						
V _{VDDA_ON} , V _{VDDB_ON}	Rising threshold VDDA_ON, VDDB_ON		12.5	13.5	14.5	V
V _{VDDA_OFF} , V _{VDDB_OFF}	Falling threshold VDDA_OFF, VDDB_OFF		11.5	12.5	13.5	V
V _{VDDA_HYS} , V _{VDDB_HYS}	Threshold hysteresis			1.0		V



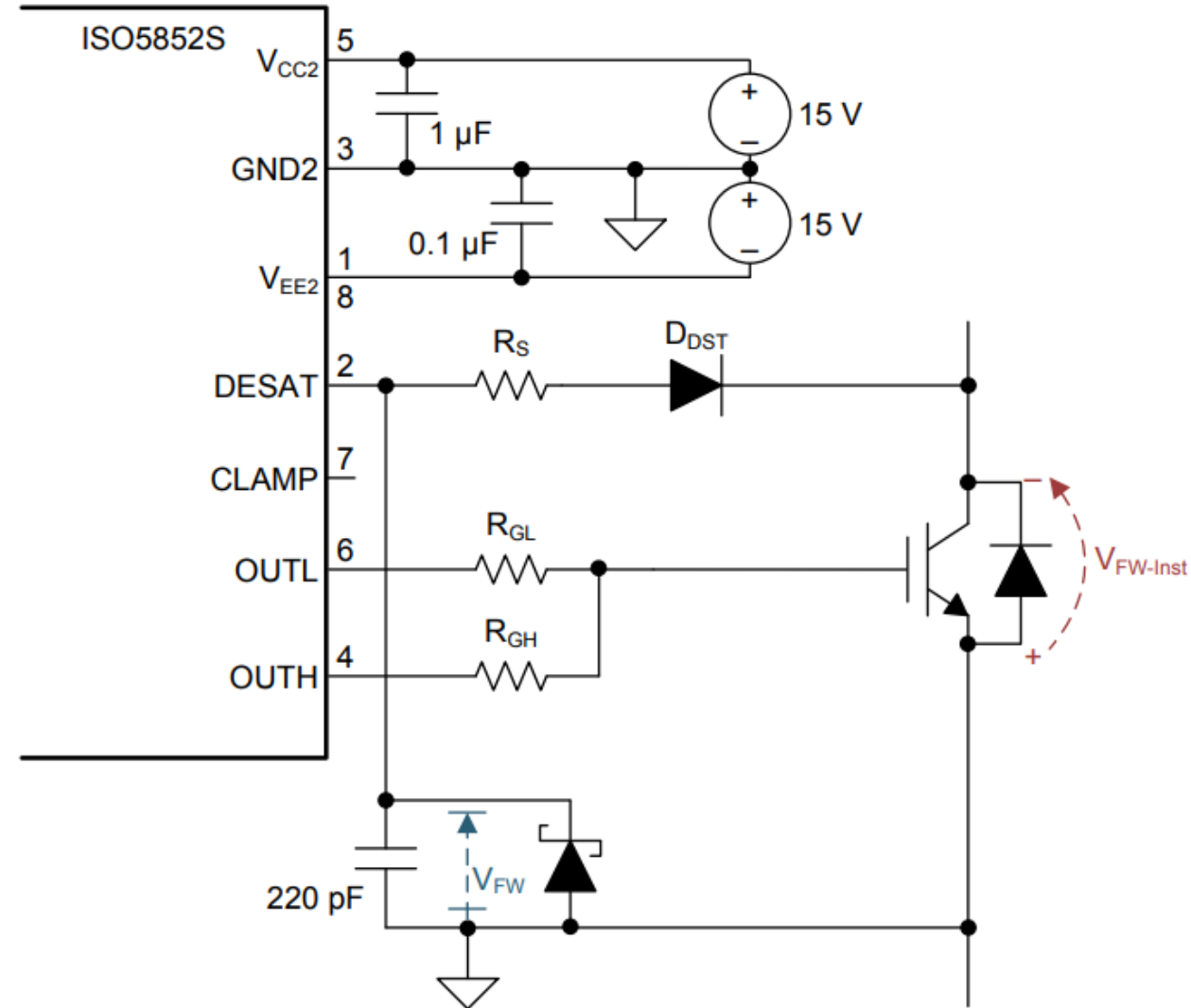
Output Challenges – Split Outputs



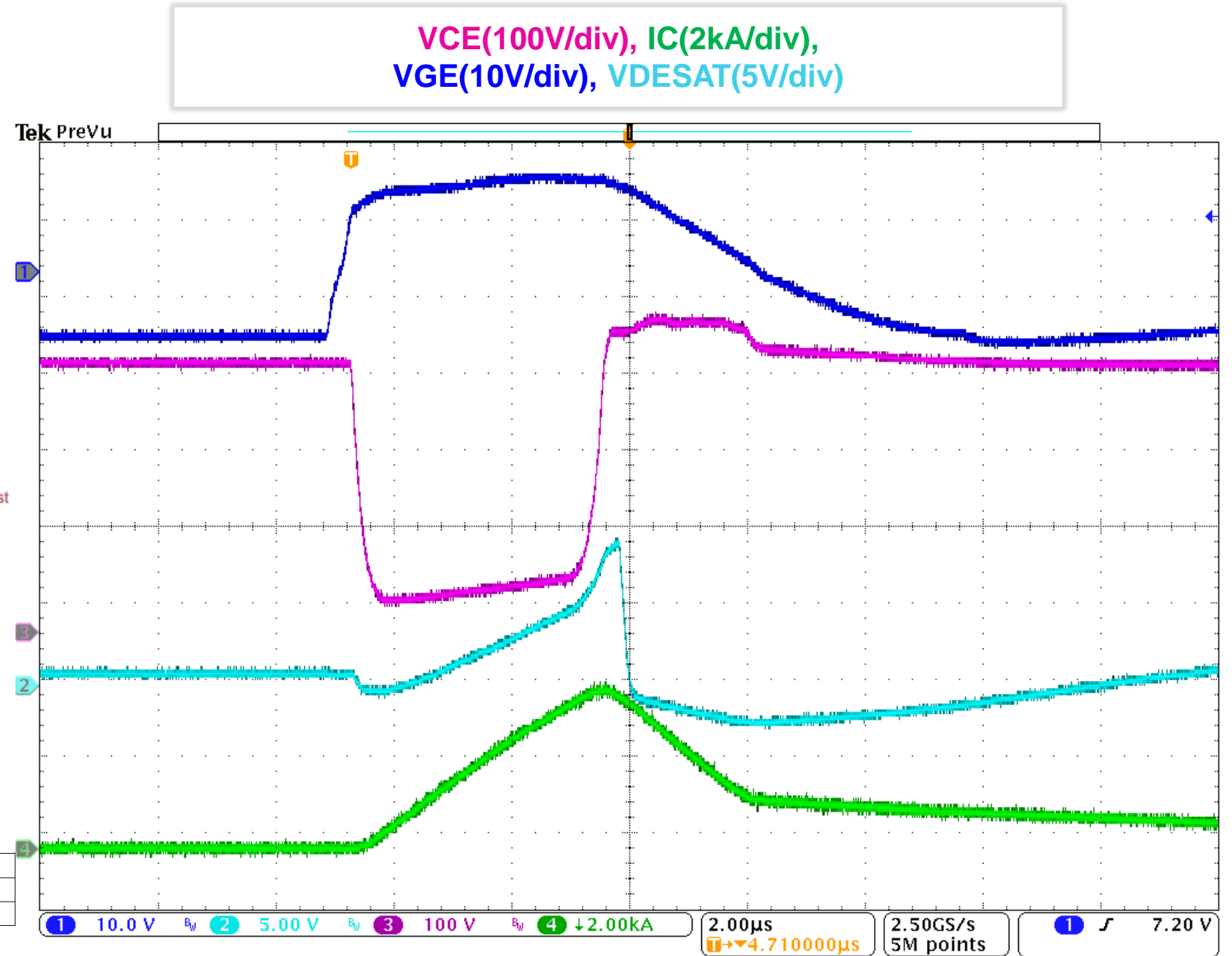
Output Challenges – Miller Clamp



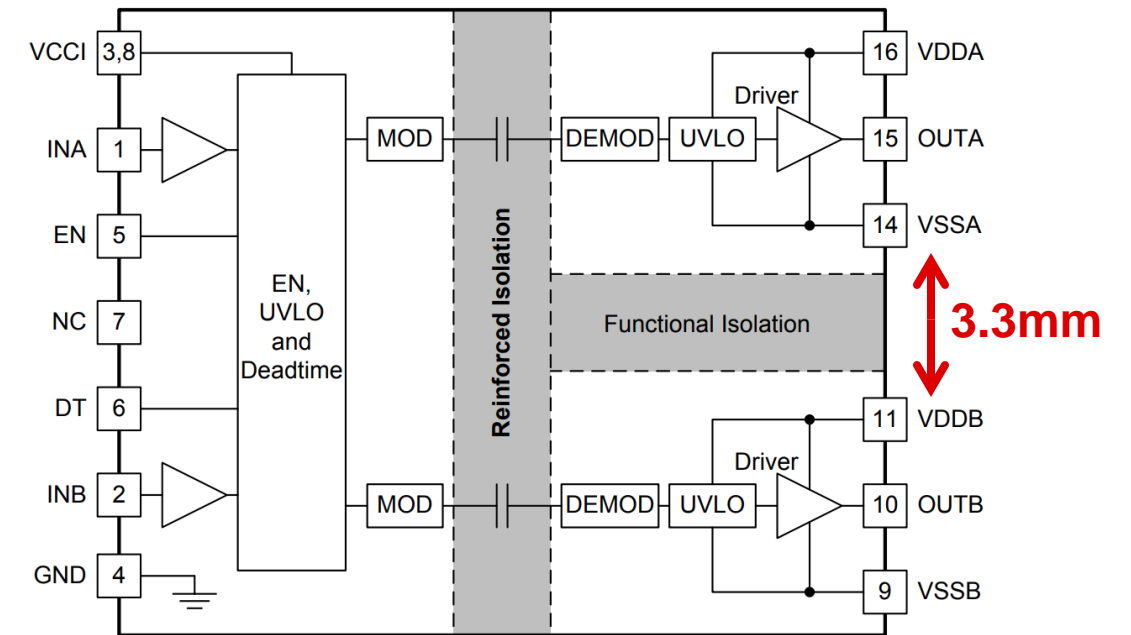
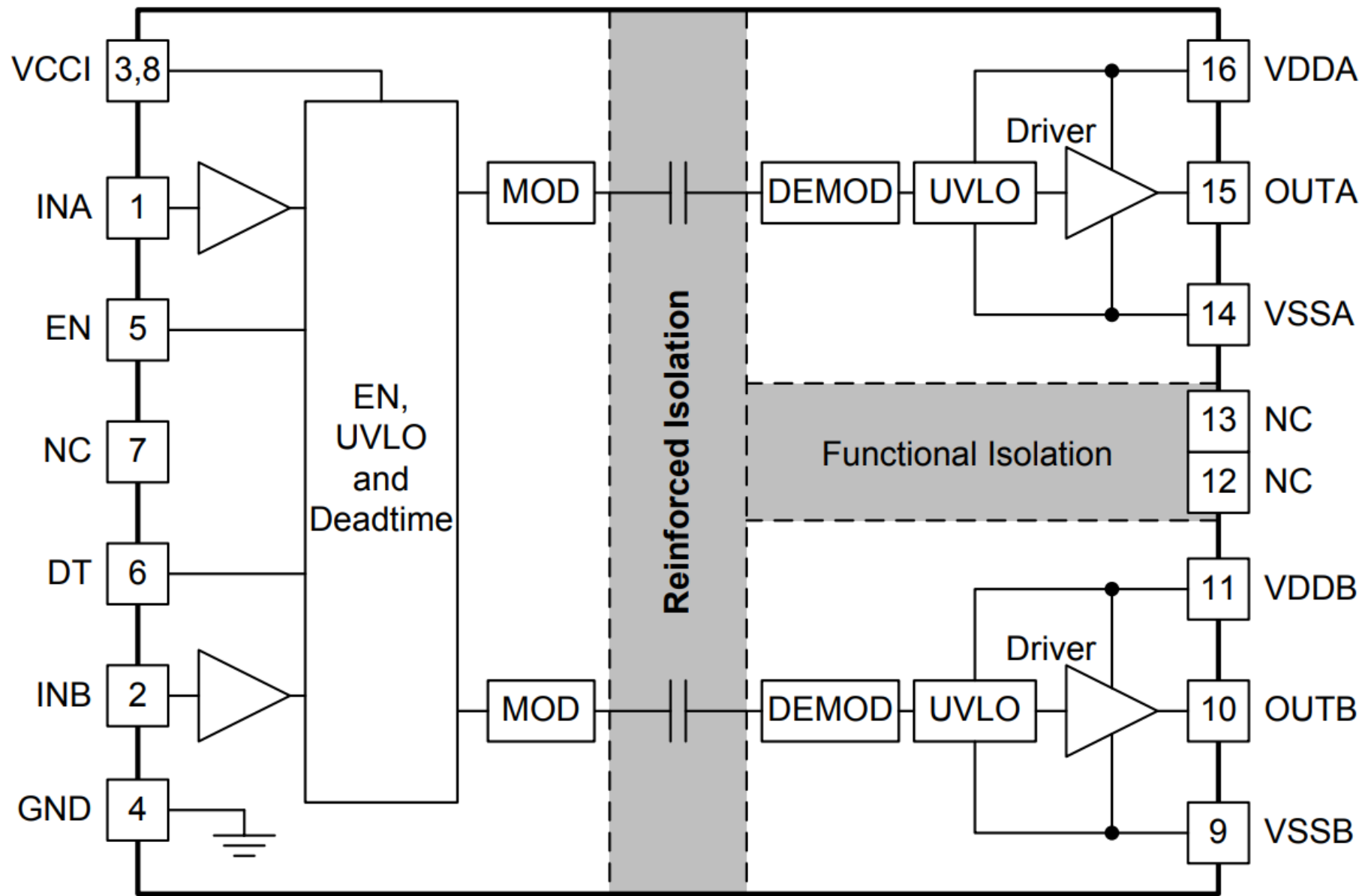
Protection Challenges – Desaturation Detection and Soft Turn Off



$t_{DS(90\%)}$	DESAT sense to 90% V_{OUTL} delay	$C_{LOAD} = 10\text{ nF}$	553	760	ns
$t_{DS(10\%)}$	DESAT sense to 10% V_{OUTL} delay	$C_{LOAD} = 10\text{ nF}$	2	3.5	μs
$t_{DS(GF)}$	DESAT-glitch filter delay	$C_{LOAD} = 1\text{ nF}$	330		ns

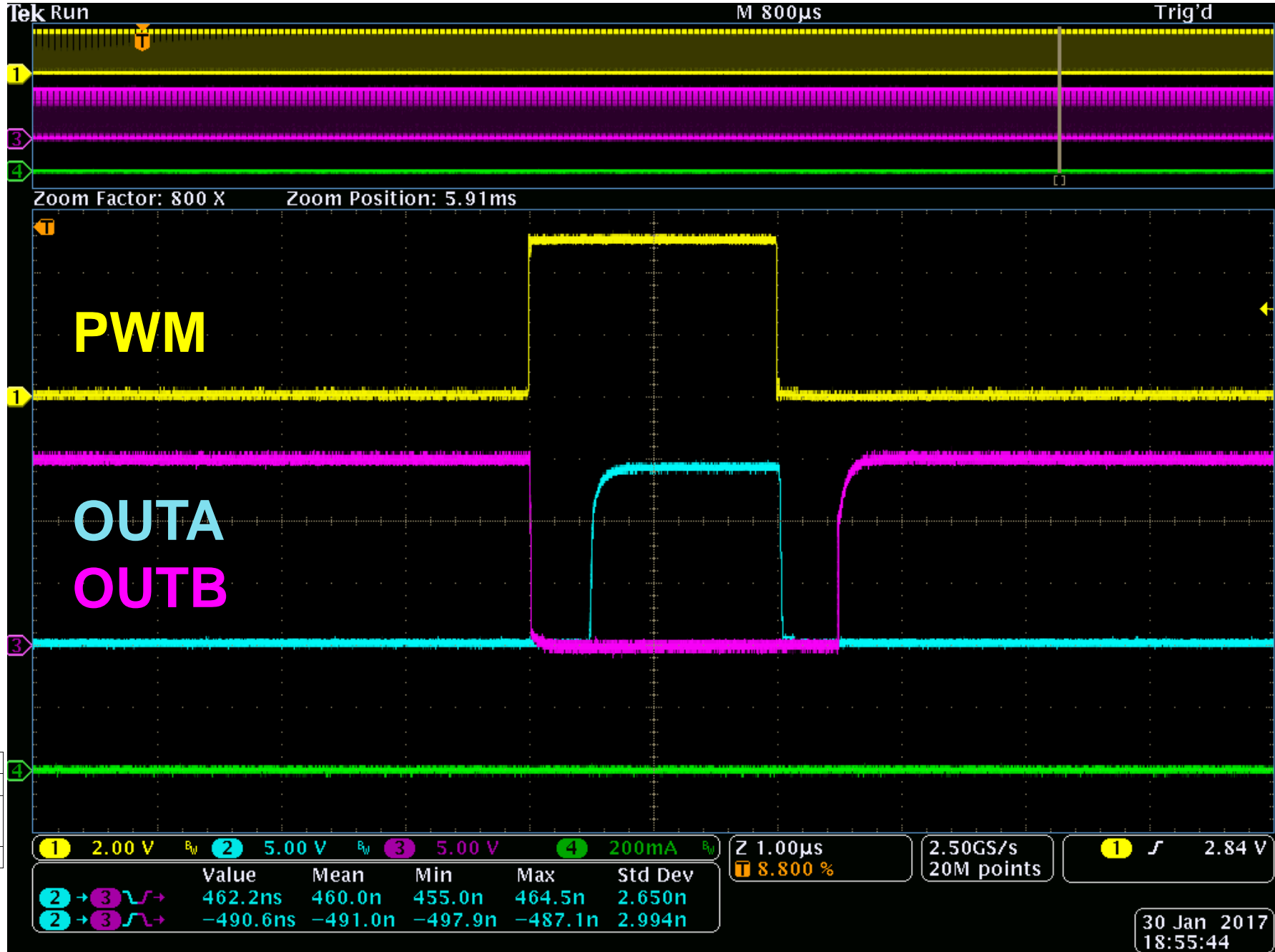
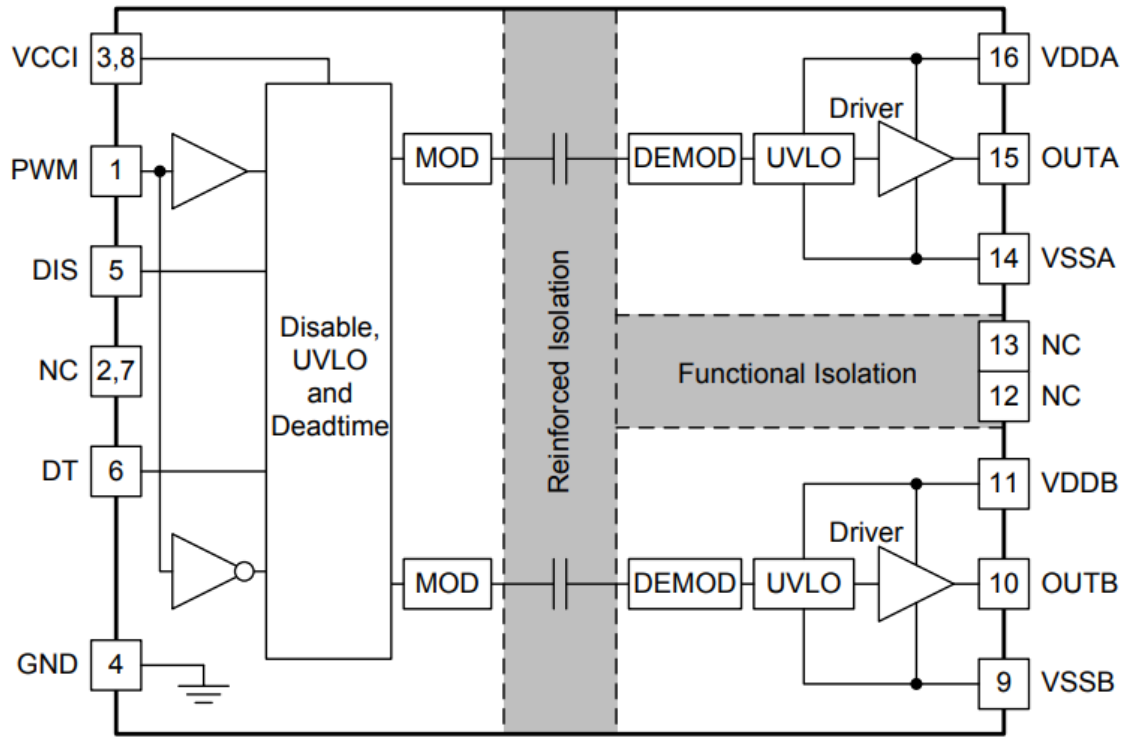


Protection Challenges – Channel-to-Channel Isolation Rating



Standard	Spacing (mm)	Voltage rating (Vrms)
IEC60950	3.3	630
IPC9592	4	800
IPC2221	2.4	800

Protection Challenges – Programmable Dead Time



Dead time	DT pin configuration	160	200	240	Unit
	Pull DT pin to VCCI	0			ns
	DT pin is left open, min spec characterized only, tested for outliers	8	15		ns
	R _{DT} = 20 kΩ	160	200	240	ns

Thanks for your time!
Please try the quiz.

Isolated Gate Driver Challenges and Solutions

Multiple Choice Quiz

TI Precision Labs – Isolation

Quiz: Isolated Gate Driver Challenges and Solutions

1. **Drivers with differential inputs can emulate an enable function with no additional circuitry by _____**
 - a. Sensing a special pattern on the input
 - b. Dropping the internal supply voltage below the UVLO threshold
 - c. Using one input as the PWM input, and the other input as an enable/disable pin
 - d. This isn't possible, an external logic gate must be used

2. **Different undervoltage lockout levels are used for _____**
 - a. Logic-level MOSFETs, power MOSFETs, and IGBTs/SiC MOSFETs
 - b. Bipolar junction transistors and MOSFETs
 - c. Power MOSFETs in parallel
 - d. Different undervoltage lockout levels are not used by gate drivers

3. **Which of these is NOT a feature designed to help drive IGBTs and SiC MOSFETs?**
 - a. Miller clamp
 - b. Split outputs
 - c. Desaturation/overcurrent detection
 - d. 8V undervoltage lockout options

Quiz: Isolated Gate Driver Challenges and Solutions

4. **The channel-to-channel isolation rating is _____**
- Only applicable for half-bridge structures
 - Unipolar (one channel must be at a higher DC voltage than the other at all times)
 - Always the same as the control-to-output isolation rating
 - Determined largely by package geometry and pin/leadframe spacing
5. **Integrated dead time control circuits _____**
- Disable the gate driver when both inputs go high, and raise a fault on the control side
 - Hold the outputs low whenever both inputs are high, and for a fixed time after one input goes low
 - Measure the duration and order of a sequence of pulses, and repeat those pulses with added dead time inserted
 - Power down the gate driver during power converter sleep mode, preventing unnecessary energy expenditure

Isolated Gate Driver Challenges and Solutions

Multiple Choice Quiz – Solutions

TI Precision Labs – Isolation

Quiz: Isolated Gate Driver Challenges and Solutions

- 1. Drivers with differential inputs can emulate an enable function with no additional circuitry by _____**
 - a. Sensing a special pattern on the input
 - b. Dropping the internal supply voltage below the UVLO threshold
 - c. Using one input as the PWM input, and the other input as an enable/disable pin**
 - d. This isn't possible, an external logic gate must be used
- 2. Different undervoltage lockout levels are used for _____**
 - a. Logic-level MOSFETs, power MOSFETs, and IGBTs/SiC MOSFETs**
 - b. Bipolar junction transistors and MOSFETs
 - c. Power MOSFETs in parallel
 - d. Different undervoltage lockout levels are not used by gate drivers
- 3. Which of these is NOT a feature designed to help drive IGBTs and SiC MOSFETs?**
 - a. Miller clamp
 - b. Split outputs
 - c. Desaturation/overcurrent detection
 - d. 8V undervoltage lockout options**

Quiz: Isolated Gate Driver Challenges and Solutions

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- a. Only applicable for half-bridge structures
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 - d. **Determined largely by package geometry and pin/leadframe spacing**
5. Integrated dead time control circuits _____
- a. Disable the gate driver when both inputs go high, and raise a fault on the control side
 - b. **Hold the outputs low whenever both inputs are high, and for a fixed time after one input goes low**
 - c. Measure the duration and order of a sequence of pulses, and repeat those pulses with added dead time inserted
 - d. Power down the gate driver during power converter sleep mode, preventing unnecessary energy expenditure